

CMOS-ILC Research Team of IReS

M. Winter

General Features

- National funding agency: CNRS - IN2P3
- Academic host institution: Univ. Louis Pasteur (Strasbourg)
- In ILC since 1998 (TESLA project)
- Develops CMOS sensors for charged tracking since 1999 (~ 20 pub. in NIM, IEEE-TNS)

► Team Composition:

- ◇ **Micro-circuit designers:** C.Colledani, A.Dorokhov (Post-doc), W.Dulinski, F.Guilloux, S.Heini (Doc.), A.Himmi, Ch.Hu, M.Szelezniak (Doc.), I.Valin
- ◇ **Test system engineers:** G.Claus, M.Goffe, K.Jaaskelainen, M.Pellicoli
- ◇ **Physicists:** J.Baudot, A.Besson, M.Deveaux (Doc.), D.Grandjean (Doc.), A.Shabetai (Doc.), M.Winter

► Activities:

- ◇ **Development of CMOS sensors for:**
 - vertex detectors : STAR-upgrade (RHIC), CBM (GSI), ILC
 - imaging devices: HPD, electronic microscopes, fluorescence microscopes, etc.
- ◇ **Studies of vertex detector geometries:**
 - for ILC
 - for CBM
- ◇ **Physics studies for ILC:**
 - Higgs-top coupling
 - HHH coupling

► Exploration of manufacturing processes:

- ∴ AMS: $0.6\mu m$, $0.35\mu m$ HIGH-RES, $0.35\mu m$ OPTO ,
- ∴ AMI (former MIETEC): $0.35\mu m$, ∴ IBM: $0.25\mu m$, ∴ TSMC: $0.25\mu m$

► Design of pixel architectures:

- ∴ charge collection systems ∴ CDS with preAMP (in coll. with DAPNIA),
- ∴ radiation tolerance (vs T) ∴ multi-memory pixels

► Design of chip (read-out) architectures:

- ∴ fast column parallel read-out with integ. ADC & sparsification (in coll. with DAPNIA, LPSC, LPCC),
- ∴ decoupled integration and read-out architecture,
- ∴ STAR specific architecture ∴ imaging specific designs

► Activities related to material budget:

- ∴ industrial thinning procedure (wafers, chips) → yield, etc.
- ∴ handling of thinned sensors (e.g. bonding)

► Activities related to radiation tolerance:

- ∴ irradiations: 1 MeV neutrons (coll. with Dubna), 10 keV X-Rays, ^{60}Co gammas, 10 MeV e^- (coll. with HH)
- ∴ R&D on radiation tolerant sensors

- ▶ 4 test benches for MIMOSA chips (VME $\mapsto$ USB-2)
 - $\hookrightarrow$ characterisation & calibration of chips (with self made DAS)

- ▶ Microstrip telescope (4 pairs of planes $\mapsto$ x,y with $\sim 1 \mu m$ accuracy in mid-plane)
 - $\hookrightarrow$ characterisation of chips on test beams ($\mapsto$ cluster charge $\rightarrow$ epitaxial thickness, ϵ_{det} , σ_{sp})

- ▶ Micro-bonding service

- ▶ Probe stations

- ▶ CMOS sensors (4 planes) for demonstrator and final set-up:
 - full design (in coll. with DAPNIA, LPSC-Grenoble, LPCC-Clermont)
 - full characterisation and performance assessment

- ▶ CMOS sensor local DAS boards:
 - provide boards for demonstrator
 - participate to final DAS concept

- ▶ Participate to overall concept, based on expertise on beam (Si-strip) telescope (W.Dulinski)